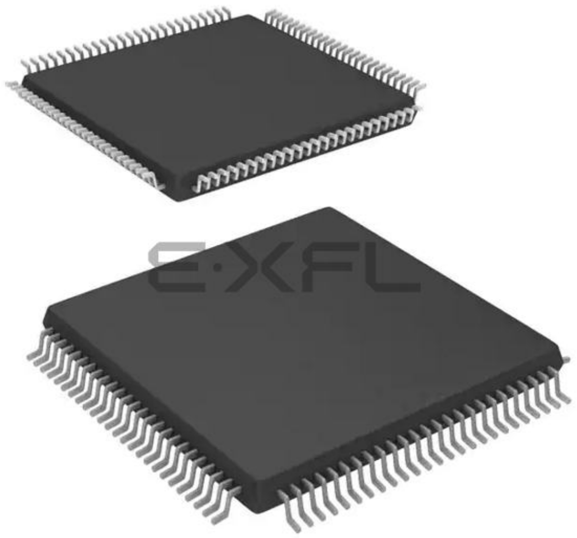
Microsemi Corporation - A1425A-1VQ100C Datasheet



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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	310
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	83
Number of Gates	2500
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a1425a-1vq100c

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Product Plan

Device/Package	Speed Grade[1]				Application[1]			
	Std.	–1	–2	–3	C	I	M	B
A1415A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	✓	D	D	✓	✓	✓	–
100-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	✓	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	✓	D	D	✓	✓	✓	–
100-Pin Ceramic Pin Grid Array (CPGA)	D	D	D	D	D	–	–	–
A14V15A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	–	–	–	✓	–	–	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	–	–	–	✓	–	–	–
A1425A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	✓	D	D	✓	✓		
100-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	–	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	✓	D	D	✓	✓	–	–
132-Pin Ceramic Quad Flatpack (CQFP)	✓	✓	–	–	✓	–	✓	✓
133-Pin Ceramic Pin Grid Array (CPGA)	D	D	D	D	D	–	D	D
160-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	–	–
A14V25A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	–	–	–	✓	–	–	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	–	–	–	✓	–	–	–
160-Pin Plastic Quad Flatpack (PQFP)	✓	–	–	–	✓	–	–	–
A1440A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	✓	D	D	✓	✓	–	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	✓	D	D	✓	✓	–	–
160-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	–	–
175-Pin Ceramic Pin Grid Array (CPGA)	D	D	D	D	D	–	–	–
176-Pin Thin Quad Flatpack (TQFP)	✓	✓	D	D	✓	✓	–	–

Notes:

1. *Applications:*
   C = Commercial
   I = Industrial
   M = Military
2. *Commercial only*

Availability:
✓ = Available
P = Planned
– = Not planned
D = Discontinued

Speed Grade:
–1 = Approx. 15% faster than Std.
–2 = Approx. 25% faster than Std.
–3 = Approx. 35% faster than Std.
(–2 and –3 speed grades have been discontinued.)

Device/Package	Speed Grade[1]				Application[1]			
	Std.	–1	–2	–3	C	I	M	B
A14V40A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	–	–	–	✓	–	–	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	–	–	–	✓	–	–	–
160-Pin Plastic Quad Flatpack (PQFP)	✓	–	–	–	✓	–	–	–
176-Pin Thin Quad Flatpack (TQFP)	✓	–	–	–	✓	–	–	–
A1460A Device								
160-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	–	–
176-Pin Thin Quad Flatpack (TQFP)	✓	✓	D	D	✓	✓	–	–
196-Pin Ceramic Quad Flatpack (CQFP)	✓	✓	–	–	✓	–	✓	✓
207-Pin Ceramic Pin Grid Array (CPGA)	✓	✓	D	D	✓	–	✓	✓
208-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	–	–
225-Pin Plastic Ball Grid Array (BGA)	D	D	D	D	D	–	–	–
A14V60A Device								
160-Pin Plastic Quad Flatpack (PQFP)	✓	–	–	–	✓	–	–	–
176-Pin Thin Quad Flatpack (TQFP)	✓	–	–	–	✓	–	–	–
208-Pin Plastic Quad Flatpack (PQFP)	✓	–	–	–	✓	–	–	–
A14100A Device								
208-Pin Power Quad Flatpack (RQFP)	✓	✓	D	D	✓	✓	–	–
257-Pin Ceramic Pin Grid Array (CPGA)	✓	✓	D	D	✓	–	✓	✓
313-Pin Plastic Ball Grid Array (BGA)	✓	✓	D	D	✓	–	–	–
256-Pin Ceramic Quad Flatpack (CQFP)	✓	✓	–	–	✓	–	✓	✓
A14V100A Device								
208-Pin Power Quad Flatpack (RQFP)	✓	–	–	–	✓	–	–	–
313-Pin Plastic Ball Grid Array (BGA)	✓	–	–	–	✓	–	–	–

Notes:

1. *Applications:*
   C = Commercial
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Speed Grade:
–1 = Approx. 15% faster than Std.
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–3 = Approx. 35% faster than Std.
(–2 and –3 speed grades have been discontinued.)

2 – Detailed Specifications

This section of the datasheet is meant to familiarize the user with the architecture of the ACT 3 family of FPGA devices. A generic description of the family will be presented first, followed by a detailed description of the logic blocks, the routing structure, the antifuses, and the special function circuits. The on-chip circuitry required to program the devices is not covered.

Topology

The ACT 3 family architecture is composed of six key elements: Logic modules, I/O modules, I/O Pad Drivers, Routing Tracks, Clock Networks, and Programming and Test Circuits. The basic structure is similar for all devices in the family, differing only in the number of rows, columns, and I/Os. The array itself consists of alternating rows of modules and channels. The logic modules and channels are in the center of the array; the I/O modules are located along the array periphery. A simplified floor plan is depicted in Figure 2-1.

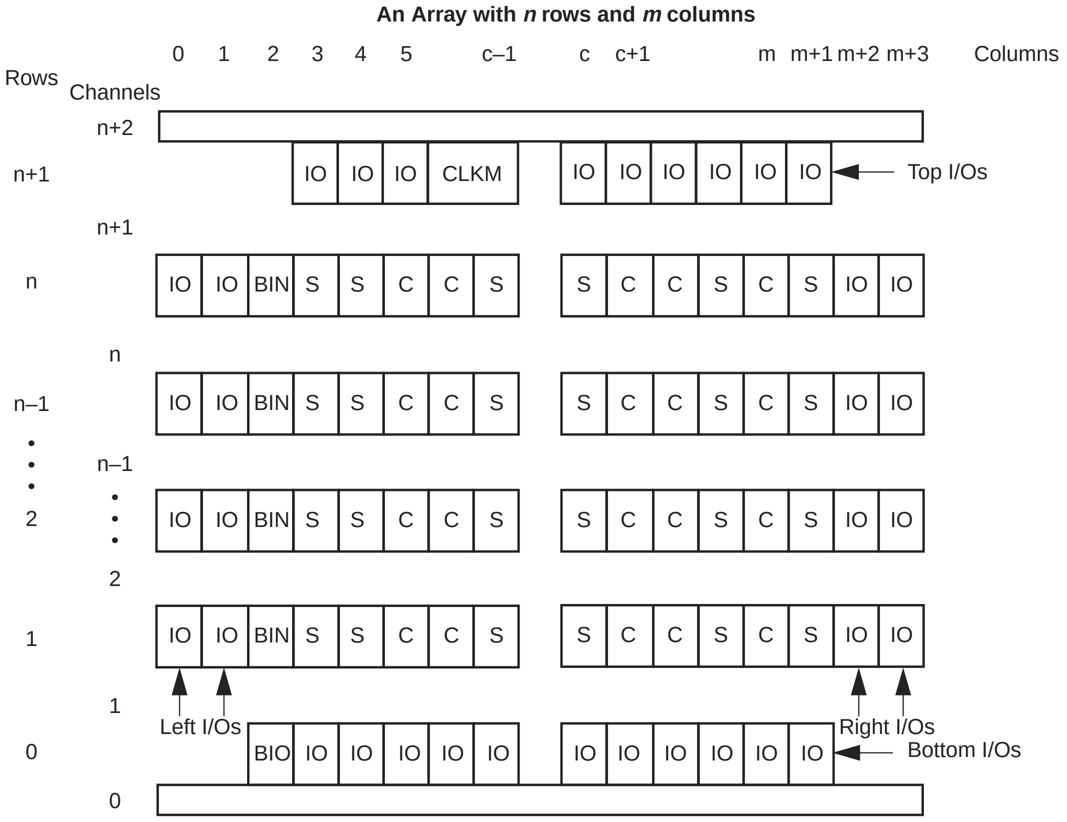


Figure 2-1 • **Generalized Floor Plan of ACT 3 Device**

Logic Modules

ACT 3 logic modules are enhanced versions of the 1200XL family logic modules. As in the 1200XL family, there are two types of modules: C-modules and S-modules (Figure 2-2 and Figure 2-3). The C-module is functionally equivalent to the 1200XL C-module and implements high fanin combinatorial macros, such as 5-input AND, 5-input OR, and so on. It is available for use as the CM8 hard macro. The S-module is designed to implement high-speed sequential functions within a single module.

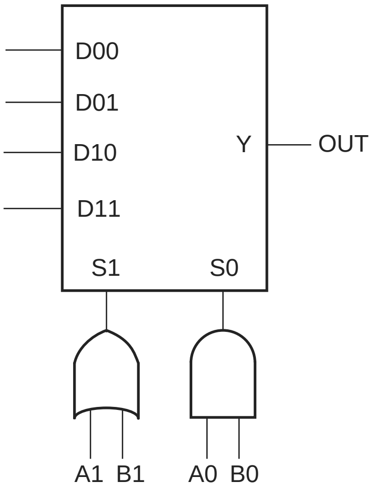


Figure 2-2 • **C-Module Diagram**

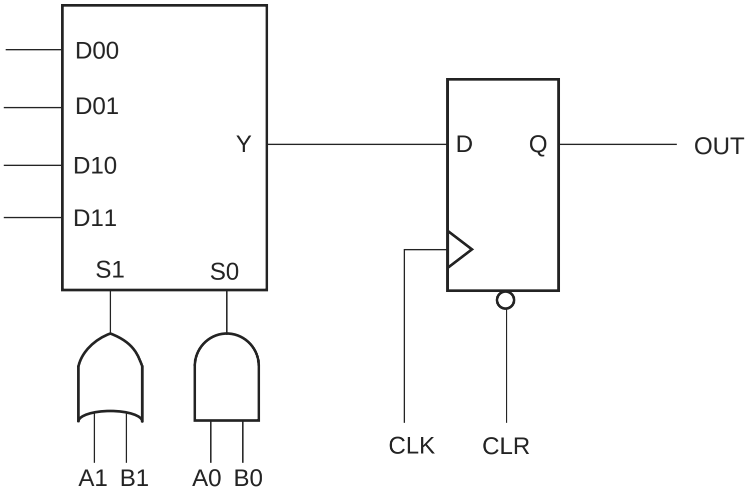


Figure 2-3 • **S-Module Diagram**

S-modules consist of a full C-module driving a flip-flop, which allows an additional level of logic to be implemented without additional propagation delay. It is available for use as the DFM8A/B and DLM8A/B hard macros. C-modules and S-modules are arranged in pairs called module-pairs. Module-pairs are arranged in alternating patterns and make up the bulk of the array. This arrangement allows the placement software to support two-module macros of four types (CC, CS, SC, and SS). The C-module implements the following function:

$$Y = !S1 * !S0 * D00 + !S1 * S0 * D01 + S1 * !S0 * D10 + S1 * S0 * D11 \tag{EQ 1}$$

where: $S0 = A0 * B0$ and $S1 = A1 + B1$

Equivalent capacitance is calculated by measuring ICC active at a specified frequency and voltage for each circuit component of interest. Measurements have been made over a range of frequencies at a fixed value of VCC. Equivalent capacitance is frequency independent so that the results may be used over a wide range of operating conditions. Equivalent capacitance values are shown in Figure 2-10.

Table 2-10 **• CEQ Values for Microsemi FPGAs**

Item	**CEQ Value**
Modules (C_{EQM})	6.7
Input Buffers (C_{EQI})	7.2
Output Buffers (C_{EQO})	10.4
Routed Array Clock Buffer Loads (C_{EQCR})	1.6
Dedicated Clock Buffer Loads (C_{EQCD})	0.7
I/O Clock Buffer Loads ($C_{EQCI)}$	0.9

To calculate the active power dissipated from the complete design, the switching frequency of each part of the logic must be known. EQ 5 shows a piece-wise linear summation over all components.

$$\begin{aligned}
&\text{Power} = VCC^2 * [(m * C_{EQM} * f_m)_{modules} + (n * C_{EQI} * f_n)_{inputs} \\
&+ (p * (C_{EQO} + C_L) * fp)\text{outputs} \\
&+ 0.5 * (q1 * C_{EQCR} * f_{q1})_{routed\_Clk1} + (r1 * fq1)_{routed\_Clk1} \\
&+ 0.5 * (q2 * C_{EQCR} * fq2)_{routed\_Clk2} \\
&+ (r_2 * f_{q2})_{routed\_Clk2} + 0.5 * (s_1 * C_{EQCD} * f_{s1})_{dedicated\_Clk} \\
&+ (s_2 * C_{EQCI} * f_{s2})_{IO\_Clk}]
\end{aligned}$$

EQ 5

Where:

m = Number of logic modules switching at f_m

n = Number of input buffers switching at f_n

p = Number of output buffers switching at f_p

q1 = Number of clock loads on the first routed array clock

q2 = Number of clock loads on the second routed array clock

r_1 = Fixed capacitance due to first routed array clock

r_2 = Fixed capacitance due to second routed array clock

s_1 = Fixed number of clock loads on the dedicated array clock

s_2 = Fixed number of clock loads on the dedicated I/O clock

C_{EQM} = Equivalent capacitance of logic modules in pF

C_{EQI} = Equivalent capacitance of input buffers in pF

C_{EQO} = Equivalent capacitance of output buffers in pF

C_{EQCR} = Equivalent capacitance of routed array clock in pF

C_{EQCD} = Equivalent capacitance of dedicated array clock in pF

C_{EQCI} = Equivalent capacitance of dedicated I/O clock in pF

C_L = Output lead capacitance in pF

f_m = Average logic module switching rate in MHz

f_n = Average input buffer switching rate in MHz

f_p = Average output buffer switching rate in MHz

f_{q1} = Average first routed array clock rate in MHz

f_{q2} = Average second routed array clock rate in MHz

f_{s1} = Average dedicated array clock rate in MHz

f_{s2} = Average dedicated I/O clock rate in MHz

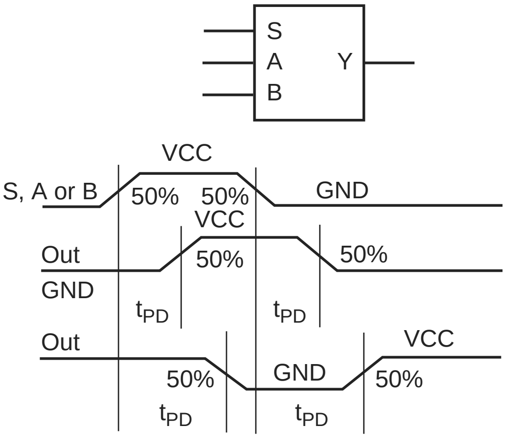


***Figure 2-14* •** **Module Delays**

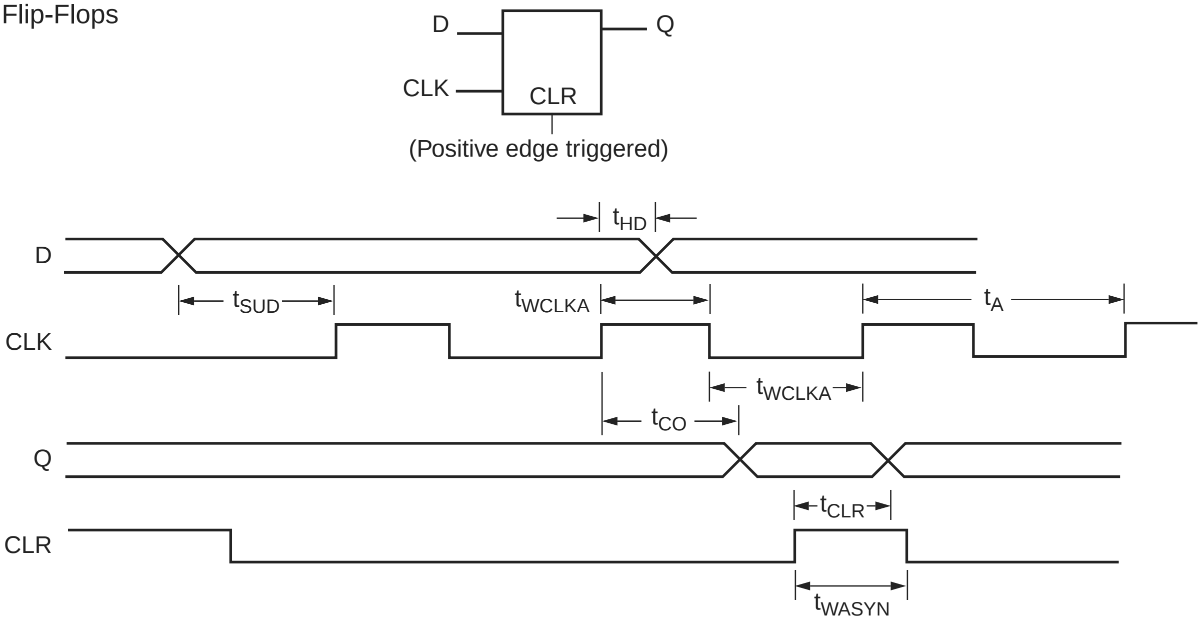


***Figure 2-15* •** **Sequential Module Timing Characteristics**

A1415A, A14V15A Timing Characteristics (continued)

***Table 2-19* • A1415A, A14V15A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

I/O Module Input Propagation Delays		**–3 Speed[1]**		**–2 Speed[1]**		**–1 Speed**		**Std. Speed**		**3.3 V Speed[2]**		**Units**
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{INY}	Input Data Pad to Y		2.8		3.2		3.6		4.2		5.5	ns
t_{ICKY}	Input Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{OCKY}	Output Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{ICLRY}	Input Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{OCLRY}	Output Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
Predicted Input Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t_{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t_{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t_{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t_{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
I/O Module Sequential Timing (wrt IOCLK pad)												
t_{INH}	Input F-F Data Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{INSU}	Input F-F Data Setup	2.0		2.3		2.5		3.0		3.0		ns
t_{IDEH}	Input Data Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{IDESU}	Input Data Enable Setup	5.8		6.5		7.5		8.6		8.6		ns
t_{OUTH}	Output F-F Data hold	0.7		0.8		0.9		1.0		1.0		ns
t_{OUTSU}	Output F-F Data Setup	0.7		0.8		0.9		1.0		1.0		ns
t_{ODEH}	Output Data Enable Hold	0.3		0.4		0.4		0.5		0.5		ns
f_{ODESU}	Output Data Enable Setup	1.3		1.5		1.7		2.0		2.0		ns

Notes:

1. *The –2 and –3 speed grades have been discontinued. Please refer to the Product Discontinuation Notices (PDNs) listed below:*

   PDN March 2001
   PDN 0104
   PDN 0203
   PDN 0604
   PDN 1004

2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*

A1425A, A14V25A Timing Characteristics

Table 2-22 • A1425A, A14V25A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C[1]

Logic Module Propagation Delays[2]		**–3 Speed[3]**		**–2 Speed[3]**		**–1 Speed**		**Std. Speed**		**3.3 V Speed[1]**		**Units**
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{PD}	Internal Array Module		2.0		2.3		2.6		3.0		3.9	ns
t_{CO}	Sequential Clock to Q		2.0		2.3		2.6		3.0		3.9	ns
t_{CLR}	Asynchronous Clear to Q		2.0		2.3		2.6		3.0		3.9	ns
Predicted Routing Delays[4]												
t_{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t_{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t_{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t_{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t_{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
Logic Module Sequential Timing												
t_{SUD}	Flip-Flop Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t_{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{SUD}	Latch Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t_{HD}	Latch Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WASYN}	Asynchronous Pulse Width	1.9		2.4		3.2		3.8		4.8		ns
t_{WCLKA}	Flip-Flop Clock Pulse Width	1.9		2.4		3.2		3.8		4.8		ns
t_A	Flip-Flop Clock Input Period	4.0		5.0		6.8		8.0		10.0		ns
f_{MAX}	Flip-Flop Clock Frequency		250		200		150		125		100	MHz

Notes:

1. *VCC = 3.0 V for 3.3 V specifications.*
2. *For dual-module macros, use* $t_{PD} + t_{RD1} + t_{PDn} + t_{CO} + t_{RD1} + t_{PDn}$ *or* $t_{PD1} + t_{RD1} + t_{SUD}$*, whichever is appropriate.*
3. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*
4. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*

A1425A, A14V25A Timing Characteristics (continued)

***Table 2-25* • A1425A, A14V25A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

Dedicated (hardwired) I/O Clock Network		**–3 Speed[1]**		**–2 Speed[1]**		**–1 Speed**		**Std. Speed**		**3.3 V Speed[1]**		**Units**
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{IOCKH}	Input Low to High (pad to I/O module input)		2.0		2.3		2.6		3.0		3.5	ns
t_{IOPWH}	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t_{IPOWL}	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t_{IOSAPW}	Minimum Asynchronous Pulse Width	1.9		2.4		3.3		3.8		4.8		ns
t_{IOCKSW}	Maximum Skew		0.4		0.4		0.4		0.4		0.4	ns
t_{IOP}	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f_{IOMAX}	Maximum Frequency		250		200		150		125		100	MHz
Dedicated (hardwired) Array Clock												
t_{HCKH}	Input Low to High (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t_{HCKL}	Input High to Low (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t_{HPWH}	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t_{HPWL}	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t_{HCKSW}	Delta High to Low, Low Slew		0.3		0.3		0.3		0.3		0.3	ns
t_{HP}	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f_{HMAX}	Maximum Frequency		250		200		150		125		100	MHz
Routed Array Clock Networks												
t_{RCKH}	Input Low to High (FO = 64)		3.7		4.1		4.7		5.5		9.0	ns
t_{RCKL}	Input High to Low (FO = 64)		4.0		4.5		5.1		6.0		9.0	ns
t_{RPWH}	Min. Pulse Width High (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t_{RPWL}	Min. Pulse Width Low (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t_{RCKSW}	Maximum Skew (FO = 128)		0.7		0.8		0.9		1.0		1.0	ns
t_{RP}	Minimum Period (FO = 64)	6.8		8.0		8.7		10.0		13.4		ns
f_{RMAX}	Maximum Frequency (FO = 64)		150		125		115		100		75	MHz
Clock-to-Clock Skews												
$t_{IOHCKSW}$	I/O Clock to H-Clock Skew	0.0	1.7	0.0	1.8	0.0	2.0	0.0	2.2	0.0	3.0	ns
$t_{IORCKSW}$	I/O Clock to R-Clock Skew (FO = 64) (FO = 80)	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	0.0 0.0	3.0 3.0	ns
t_{HRCKSW}	H-Clock to R-Clock Skew (FO = 64) (FO = 80)	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	ns

Notes:

1. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*
2. *Delays based on 35 pF loading.*

A1460A, A14V60A Timing Characteristics (continued)

***Table 2-31* • A1460A, A14V60A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

I/O Module Input Propagation Delays		**–3 Speed[1]**		**–2 Speed[1]**		**–1 Speed**		**Std. Speed**		**3.3 V Speed[1]**		**Units**
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{INY}	Input Data Pad to Y		2.8		3.2		3.6		4.2		5.5	ns
t_{ICKY}	Input Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{OCKY}	Output Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{ICLRY}	Input Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{OCLRY}	Output Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
Predicted Input Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t_{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t_{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t_{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t_{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
I/O Module Sequential Timing (wrt IOCLK pad)												
t_{INH}	Input F-F Data Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{INSU}	Input F-F Data Setup	1.3		1.5		1.8		2.0		2.0		ns
t_{IDEH}	Input Data Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{IDESU}	Input Data Enable Setup	5.8		6.5		7.5		8.6		8.6		ns
t_{OUTH}	Output F-F Data hold	0.7		0.8		0.9		1.0		1.0		ns
t_{OUTSU}	Output F-F Data Setup	0.7		0.8		0.9		1.0		1.0		ns
t_{ODEH}	Output Data Enable Hold	0.3		0.4		0.4		0.5		0.5		ns
f_{ODESU}	Output Data Enable Setup	1.3		1.5		1.7		2.0		2.0		ns

Notes:

5. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*
6. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*

A1460A, A14V60A Timing Characteristics (continued)

Table 2-32 • **A1460A, A14V60A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

I/O Module – TTL Output Timing[1]		–3 Speed[2]		–2 Speed[2]		–1 Speed		Std. Speed		3.3 V Speed[1]		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{DHS}	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t_{DLS}	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t_{ENZHS}	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t_{ENZLS}	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{ENHSZ}	Enable to Pad, H/L to Z, High Slew		7.8		8.7		9.9		11.6		15.1	ns
t_{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{CKHS}	IOCLK Pad to Pad H/L, High Slew		9.0		9.0		10.0		11.5		15.0	ns
t_{CKLS}	IOCLK Pad to Pad H/L, Low Slew		12.8		12.8		15.3		17.0		22.1	ns
d_{TLHHS}	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d_{TLHLS}	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d_{THLHS}	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d_{THLLS}	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Module – CMOS Output Timing[1]												
t_{DHS}	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t_{DLS}	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t_{ENZHS}	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t_{ENZLS}	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t_{ENHSZ}	Enable to Pad, H/L to Z, High Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{CKHS}	IOCLK Pad to Pad H/L, High Slew		10.4		10.4		12.1		13.8		17.9	ns
t_{CKLS}	IOCLK Pad to Pad H/L, Low Slew		14.5		14.5		17.4		19.3		25.1	ns
d_{TLHHS}	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d_{TLHLS}	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d_{THLHS}	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d_{THLLS}	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

Notes:

1. *Delays based on 35 pF loading.*
2. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*

A14100A, A14V100A Timing Characteristics (continued)

Table 2-35 • **A14100A, A14V100A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

I/O Module Input Propagation Delays		**–3 Speed[1]**		**–2 Speed[1]**		**–1 Speed**		**Std. Speed**		**3.3 V Speed[1]**		**Units**
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{INY}	Input Data Pad to Y		2.8		3.2		3.6		4.2		5.5	ns
t_{ICKY}	Input Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{OCKY}	Output Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{ICLRY}	Input Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{OCLRY}	Output Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
Predicted Input Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t_{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t_{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t_{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t_{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
I/O Module Sequential Timing (wrt IOCLK pad)												
t_{INH}	Input F-F Data Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{INSU}	Input F-F Data Setup	1.2		1.4		1.5		1.8		1.8		ns
t_{IDEH}	Input Data Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{IDESU}	Input Data Enable Setup	5.8		6.5		7.5		8.6		8.6		ns
t_{OUTH}	Output F-F Data hold	0.7		0.8		1.0		1.0		1.0		ns
t_{OUTSU}	Output F-F Data Setup	0.7		0.8		1.0		1.0		1.0		ns
t_{ODEH}	Output Data Enable Hold	0.3		0.4		0.5		0.5		0.5		ns
f_{ODESU}	Output Data Enable Setup	1.3		1.5		2.0		2.0		2.0		ns

*Notes: **

1. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*
2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*

Pin Descriptions

CLKA Clock A (Input)

Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

CLKB Clock B (Input)

Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

GND Ground

LOW supply voltage.

HCLK Dedicated (Hard-wired) Array Clock (Input)

Clock input for sequential modules. This input is directly wired to each S-Module and offers clock speeds independent of the number of S-Modules being driven. This pin can also be used as an I/O.

I/O Input/Output (Input, Output)

The I/O pin functions as an input, output, three-state, or bidirectional buffer. Input and output levels are compatible with standard TTL and CMOS specifications. Unused I/O pins are tristated by the Designer Series software.

IOCLK Dedicated (Hard-wired) I/O Clock (Input)

Clock input for I/O modules. This input is directly wired to each I/O module and offers clock speeds independent of the number of I/O modules being driven. This pin can also be used as an I/O.

IOPCL Dedicated (Hard-wired) I/O Preset/Clear (Input)

Input for I/O preset or clear. This global input is directly wired to the preset and clear inputs of all I/O registers. This pin functions as an I/O when no I/O preset or clear macros are used.

MODE Mode (Input)

The MODE pin controls the use of diagnostic pins (DCLK, PRA, PRB, SDI). When the MODE pin is HIGH, the special functions are active. When the MODE pin is LOW, the pins function as I/Os. To provide Actionprobe capability, the MODE pin should be terminated to GND through a 10K resistor so that the MODE pin can be pulled high when required.

NC No Connection

This pin is not connected to circuitry within the device.

PRA Probe A (Output)

The Probe A pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe B pin to allow real-time diagnostic output of any signal path within the device. The Probe A pin can be used as a user-defined I/O when debugging has been completed. The pin’s probe capabilities can be permanently disabled to protect programmed design confidentiality. PRA is accessible when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

PRB Probe B (Output)

The Probe B pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe A pin to allow real-time diagnostic output of any signal path within the device. The Probe B pin can be used as a user-defined I/O when debugging has been completed. The pin’s probe capabilities can be permanently disabled to protect programmed design confidentiality. PRB is accessible when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

SDI Serial Data Input (Input)

Serial data input for diagnostic probe and device programming. SDI is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

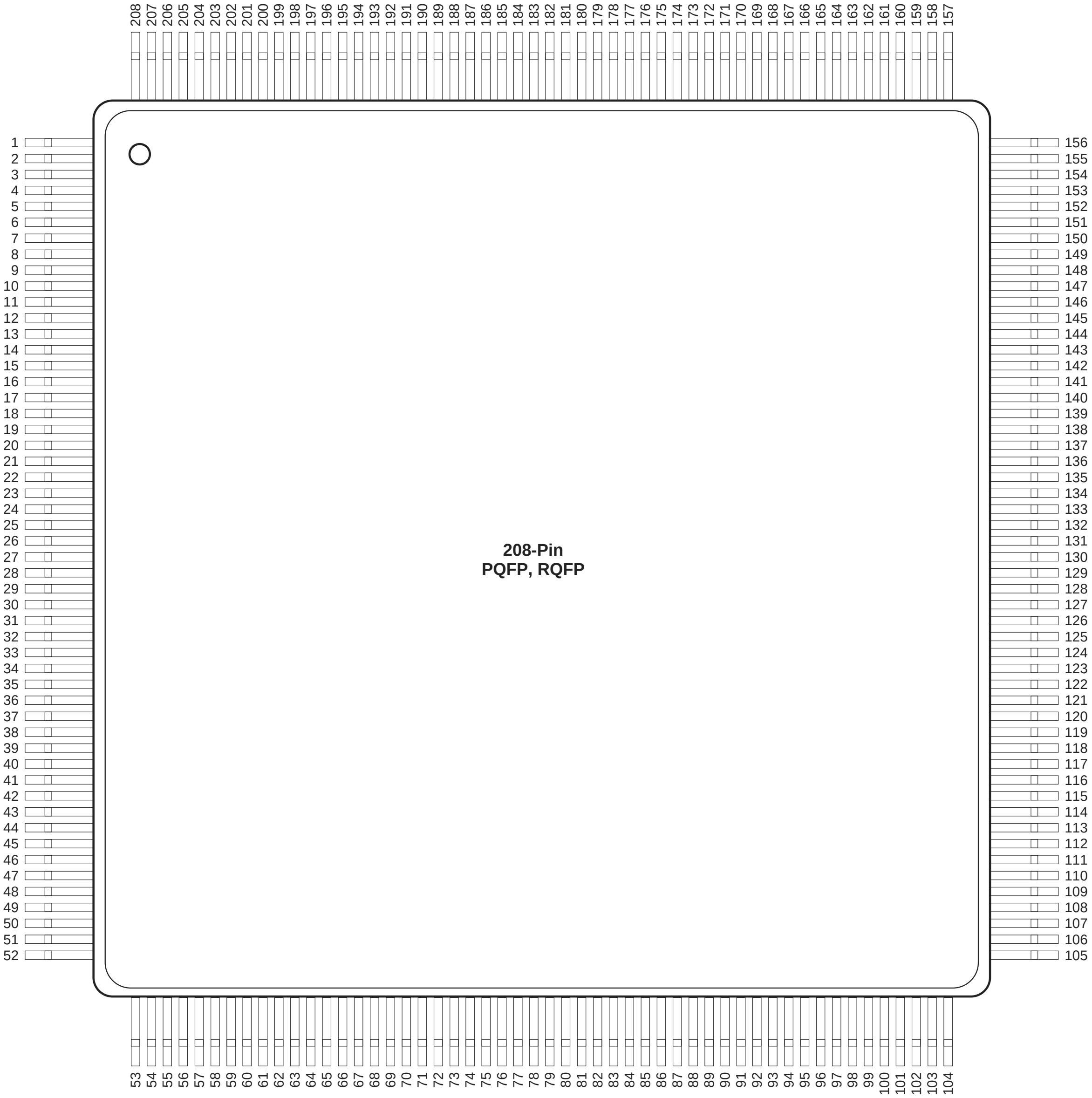
PL84			
Pin Number	**A1415, A14V15 Function**	**A1425, A14V25 Function**	**A1440, A14V40 Function**
1	VCC	VCC	VCC
2	GND	GND	GND
3	VCC	VCC	VCC
4	PRA, I/O	PRA, I/O	PRA, I/O
11	DCLK, I/O	DCLK, I/O	DCLK, I/O
12	SDI, I/O	SDI, I/O	SDI, I/O
16	MODE	MODE	MODE
27	GND	GND	GND
28	VCC	VCC	VCC
40	PRB, I/O	PRB, I/O	PRB, I/O
41	VCC	VCC	VCC
42	GND	GND	GND
43	VCC	VCC	VCC
45	HCLK, I/O	HCLK, I/O	HCLK, I/O
52	SDO	SDO	SDO
53	IOPCL, I/O	IOPCL, I/O	IOPCL, I/O
59	VCC	VCC	VCC
60	VCC	VCC	VCC
61	GND	GND	GND
68	VCC	VCC	VCC
69	GND	GND	GND
74	IOCLK, I/O	IOCLK, I/O	IOCLK, I/O
83	CLKA, I/O	CLKA, I/O	CLKA, I/O
84	CLKB, I/O	CLKB, I/O	CLKB, I/O

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

PQ160			
Pin Number	**A1425, A14V25 Function**	**A1440, A14V40 Function**	**A1460, A14V60 Function**
1	GND	GND	GND
2	SDI, I/O	SDI, I/O	SDI, I/O
5	NC	I/O	I/O
9	MODE	MODE	MODE
10	VCC	VCC	VCC
14	NC	I/O	I/O
15	GND	GND	GND
18	VCC	VCC	VCC
19	GND	GND	GND
20	NC	I/O	I/O
24	NC	I/O	I/O
27	NC	I/O	I/O
28	VCC	VCC	VCC
29	VCC	VCC	VCC
40	GND	GND	GND
41	NC	I/O	I/O
43	NC	I/O	I/O
45	NC	I/O	I/O
46	VCC	VCC	VCC
47	NC	I/O	I/O
49	NC	I/O	I/O
51	NC	I/O	I/O
53	NC	I/O	I/O
58	PRB, I/O	PRB, I/O	PRB, I/O
59	GND	GND	GND
60	VCC	VCC	VCC
62	HCLK, I/O	HCLK, I/O	HCLK, I/O
63	GND	GND	GND
74	NC	I/O	I/O
75	VCC	VCC	VCC
76	NC	I/O	I/O
77	NC	I/O	I/O
78	NC	I/O	I/O
79	SDO	SDO	SDO
80	IOPCL, I/O	IOPCL, I/O	IOPCL, I/O
81	GND	GND	GND
90	VCC	VCC	VCC
91	VCC	VCC	VCC

PQ208, RQ208



Note: This is the top view of the package

Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx

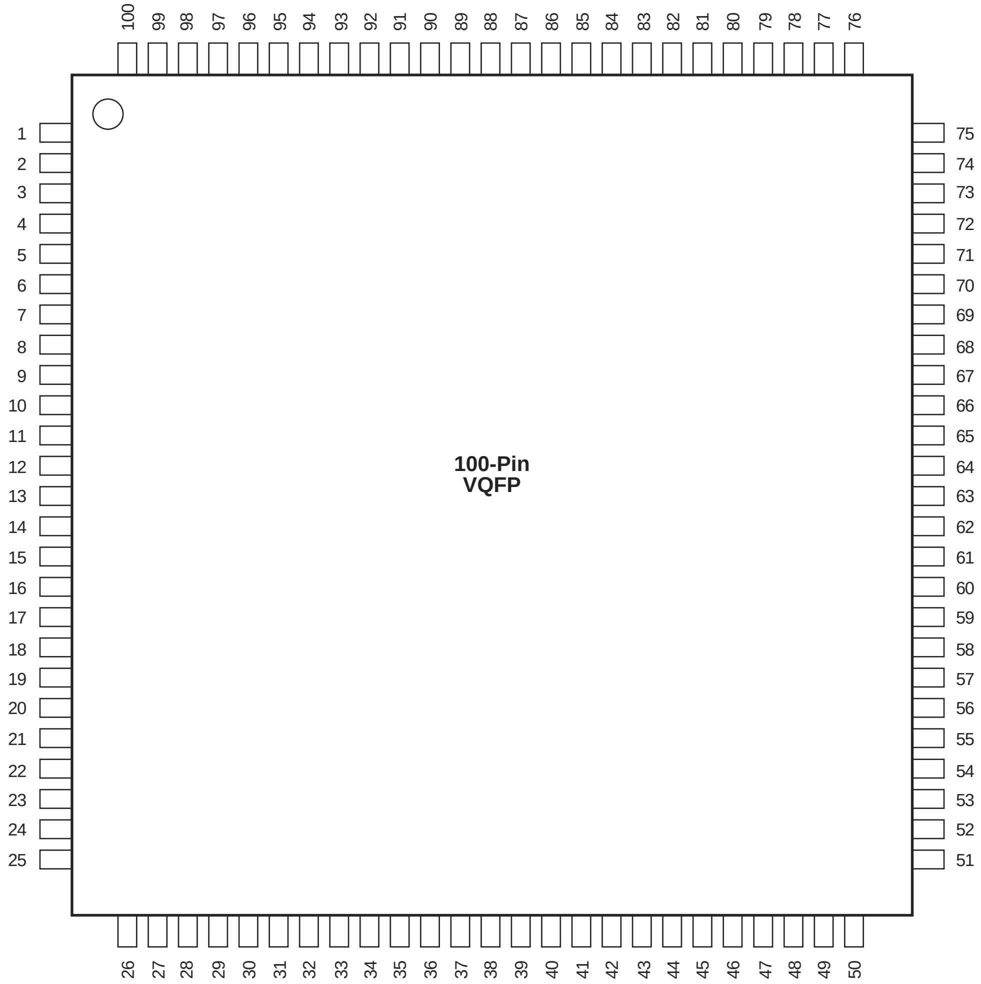
PQ208, RQ208		
Pin Number	**A1460, A14V60 Function**	**A14100, A14V100 Function**
1	GND	GND
2	SDI, I/O	SDI, I/O
11	MODE	MODE
12	VCC	VCC
25	VCC	VCC
26	GND	GND
27	VCC	VCC
28	GND	GND
40	VCC	VCC
41	VCC	VCC
52	GND	GND
53	NC	I/O
60	VCC	VCC
65	NC	I/O
76	PRB, I/O	PRB, I/O
77	GND	GND
78	VCC	VCC
79	GND	GND
80	VCC	VCC
82	HCLK, I/O	HCLK, I/O
98	VCC	VCC
102	NC	I/O
103	SDO	SDO
104	IOPCL, I/O	IOPCL, I/O
105	GND	GND
114	VCC	VCC

PQ208, RQ208		
Pin Number	**A1460, A14V60 Function**	**A14100, A14V100 Function**
115	VCC	VCC
116	NC	I/O
129	GND	GND
130	VCC	VCC
131	GND	GND
132	VCC	VCC
145	VCC	VCC
146	GND	GND
147	NC	I/O
148	VCC	VCC
156	IOCLK, I/O	IOCLK, I/O
157	GND	GND
158	NC	I/O
164	VCC	VCC
180	CLKA, I/O	CLKA, I/O
181	CLKB, I/O	CLKB, I/O
182	VCC	VCC
183	GND	GND
184	VCC	VCC
185	GND	GND
186	PRA, I/O	PRA, I/O
195	NC	I/O
201	VCC	VCC
205	NC	I/O
208	DCLK, I/O	DCLK, I/O

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

VQ100

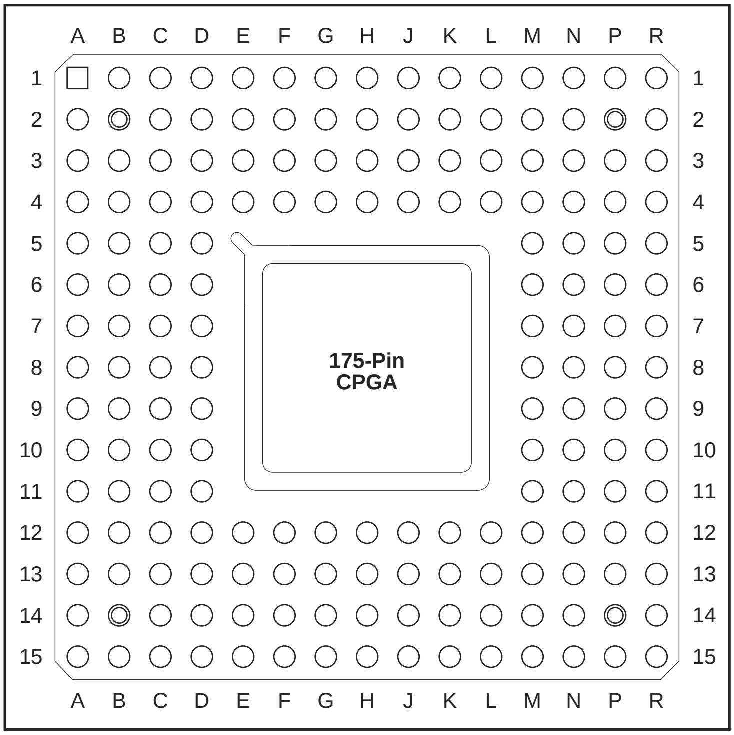


Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx

PG175



Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx

4 – Datasheet Information

List of Changes

The following table lists critical changes that were made in each version of the datasheet.

Revision	Changes	Page
Revision 3 (January 2012)	The description for SDO pins had earlier been removed from the datasheet and has now been included again, in the "Pin Descriptions" section (SAR 35820).	2-21
	SDO pin numbers had earlier been removed from package pin assignment tables in the datasheet, and have now been restored to the pin tables (SAR 35820).	3-1
Revision 2 (September 2011)	The ACT 3 datasheet was formatted newly in the style used for current datasheets. The same information is present (other than noted in the list of changes for this revision) but divided into chapters.	N/A
	The datasheet was revised to note in multiple places that speed grades –2 and –3 have been discontinued. The following device/package combinations have been discontinued for all speed grades and temperatures (SAR 33872): A1415 PG100 A1425 PG133 A1440 PG175 A1460 BG225 Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004.	I and others
	The "Features" section was revised to state the clock-to-ouput time and on-chip performance for –1 speed grade as 9.0 ns and 186 MHz. The "General Description" section was revised in accordance (SAR 33872).	I
	The maximum performance values were updated in Table 1 • ACT 3 Family Product Information, and now reflect worst-case commercial for the –1 speed grade (SAR 33872).	I
	The "Product Plan" table was updated as follows to conform to current offerings (SAR 33872): The A1415A device is offered in PL84, PG100, and VQ100 packages for Military application. The A1440A device is offered in TQ176 and VQ100 packages for Industrial application.	III
	Table 1-1 • Chip-to-Chip Performance (worst-case commercial) was updated to include data for all speed grades instead of only –3 (SAR 33872).	1-2
	Figure 1-1 • Predictable Performance (worst-case commercial, –1 speed grade) was revised to reflect values for the –1 speed grade (SAR 33872).	1-1
	Figure 2-10 • Timing Model was updated to show data for the –1 speed grade instead of –3 (SAR 33872).	2-16
	Table 2-14 • Logic Module and Routing Delay by Fanout (ns); Worst-Case Commercial Conditions was updated to include data for all speed grades instead of only –3 (SAR 33872).	2-20
	Package names used in the "Package Pin Assignments" section and throughout the document were revised to match standards given in *Package Mechanical Drawings* (SAR 27395).	3-1